# C67401 C67401A C67402 C67402A

First-In First-Out (FIFO) 64x4, 64x5 Cascadable Memory

#### DISTINCTIVE CHARACTERISTICS

- Choice of 15 and 10 MHz shift-out/shift-in rates
- · Choice of 4-bit or 5-bit data width
- TTL inputs and outputs
- Readily expandable in the word and bit dimensions
- Structured pinouts. Output pins directly opposite corresponding input pins
- Asynchronous operation

#### **ORDERING INFORMATION**

Part Number	Package	Temp	Description
C67401	CD 016,PD 016,PL 020	Com	10 MHz 64x4 FIFO
C67402	CD 018,PD 018,PL 020	Com	10 MHz 64x5 FIFO
C67401A	CD 016,PD 016,PL 020	Com	15 MHz 64x4 FIFO
C67402A	CD 018,PD 018,PL 020	Com	15MHz 64x5 FIFO

Advanced

Micro

**Devices** 

#### **GENERAL DESCRIPTION**

The C67401/2/1A/2A are "fall-through" high speed First-In First-Out (FIFO) memory organized 64 words by 4 bits and 64 words by 5 bits respectively. A 15 MHz data rate allows usage in high speed tape or disc controllers and communications buffer applications. Both word length and FIFO depth are expandable.

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#### CONNECTION DIAGRAMS



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# **ABSOLUTE MAXIMUM RATINGS**

Supply voltage, Vcc	0.5 V to + 7.0 V
Input voltage	1.5 V to + 7.0 V
Off-state output voltage	0.5 V to + 5.5 V
Storage temperature	65°C to + 150°C

#### **OPERATING CONDITIONS**

Symbol	Parameter	Figure	C67401A/2A Min. Typ. Max.			C67401/2 Min. Typ. Max.			Unit
V <sub>cc</sub>	Supply voltage	- igure	4.75	<u>- 190.</u> 5	5.25	4.75	5	5.25	V
TA	Operating free-air temperature		0		75	0		75	°C
t <sub>siH</sub> t	Shift in HIGH time	1	23			23			ns
t <sub>SIL</sub>	Shift in LOW time	1	25			35			ns
t <sub>IDS</sub>	Input data setup	1	0			0			ns
t <sub>IDH</sub>	Input data hold time	1	40			45			ns
t <sub>son</sub> †	Shift Out HIGH time	5	23			23		1.1.1.11	ns
t <sub>SOL</sub>	Shift Out LOW time	5	25			35			ns
t <sub>MRW</sub>	Master Reset pulse	10	35			35			ns
t <sub>MRS</sub>	Master Reset to SI	10	35			35			ns

### SWITCHING CHARACTERISTICS Over Operating Conditions

			C6	7401A/2A	(		
Symbol	Parameter	Figure	Min.	Тур. Мах.	Min.	Тур. Мах.	Unit
f <sub>IN</sub>	Shift In rate	1	15		10		MHz
t <sub>IRL</sub>	Shift In to Input Ready LOW	1		40		45	ns
t <sub>IAH</sub>	Shift In to Input Ready HIGH	1		40		45	ns
f <sub>OUT</sub>	Shift Out rate	5	15		10		MHz
t <sub>ORL</sub> †	Shift Out to Output Ready LOW	5		45		55	ns
t <sub>ORH</sub> †	Shift Out to Output Ready HIGH	5		50		60	ns
t <sub>орн</sub>	Output Data Hold (previous word)	5	10		10		ns
t <sub>ops</sub>	Output Data Shift (next word)	5	1	45		55	ns
t <sub>PT</sub>	Data throughput or "fall through"	4,8		1.6		3	μs
t <sub>MRORL</sub>	Master Reset to OR LOW	10		60		60	ns
t <sub>MRIRH</sub>	Master Reset to IR HIGH	10		60		60	ns
t <sub>IPH</sub>	Input Ready pulse HIGH	4	23		23		ns
t <sub>орн</sub> *	Output Ready pulse HIGH	8	23		23		ns

† See AC test and High Speed application note.

\* The"TEST POINT" is driven by the output under test,

\*This parameter applies to FIFOs communicating with each other in a cascaded mode.

#### SWITCHING TEST CIRCUIT

and observed by instrumentation.



Input Pulse 0 to 3 V Input Rise and Fall Time (10% - 90%) 5 ns minimum Measurements made at 1.5 V

SYMBOL	PARAMI	ETER	TEST CONDITIONS		MIN	TYP MAX	UNIT
VIL	Low-level input	voltage				0.8†	v
v <sub>iH</sub>	High-level input voltage				2†		v
VIC	input clamp voltage		V <sub>CC</sub> = MIN	l <sub>i</sub> ≖ −18mA		-1.5	v
I <sub>IL1</sub>	Low-level	Do-Dn, MR		V <sub>1</sub> = 0.45V		-0.8	mA
IL2	input current	SI, SO	V <sub>CC</sub> = MAX			-1.6	mA
Чн	High-level input current V <sub>CC</sub> = MAX		V <sub>1</sub> = 2.4V		50	μA	
ų	Maximum input	current '	VCC = MAX	V <sub>1</sub> = 5.5V		1	mA
VOL	Low-level output voltage V <sub>CC</sub> =		V <sub>CC</sub> = MIN	I <sub>OL</sub> = 8mA		0.5	V
Voн	High-level output voltage		V <sub>CC</sub> = MIN	<sup>1</sup> OH = +0.9mA	2.4		v
los	Output short-circuit current *		V <sub>CC</sub> = MAX	V <sub>0</sub> = 0V	-20	- 90	mA
	Supply current		V <sub>CC</sub> = MAX All inputs low. All outputs open.	C67401		160	
laa				C67402		180	mA
'cc				C67401A		170	]
				C6702A		190	]

#### DC CHARACTERISTICS Over Operating Conditions

\*Not more than one output should be shorted at a time and duration of the short-circuit should not exceed one second. +There are absolute voltage with respect to device GND (Pin 8 or 9) and includes all overshoots due to test equipment

#### **FUNCTIONAL DESCRIPTION**

#### **Data Input**

After power up the Master Reset is pulsed low (Fig. 10) to prepare the FIFO to accept data in the first location. When Input Ready (IR) is HIGH the location is ready to accept data from the  $D_x$  inputs. Data then present at the data inputs is entered into the first location when the Shift In (SI) is brought HIGH. A SI HIGH signal causes the IR to go LOW. Data remains at the first location until SI is brought LOW. When SI is brought LOW and the FIFO is not full, IR will go HIGH, indicating that more room is available. Simultaneously, data will propagate to the second location and continue shifting until it reaches the output stage or a full location. The first word is present at the outputs before a shift out is applied. If the memory is full, IR will remain LOW.

#### **Data Transfer**

Once data is entered into the second cell, the transfer of any full cell to the adjacent (downstream) empty cell is automatic, activated by an on-chip control. Thus data will stack up at the end of the device while empty locations will "bubble" to the front. tpp defines the time required for the first data to travel from input to the output of a previously empty device.

#### Data Output

Data is read from the O<sub>X</sub> outputs. When data is shifted to the output stage, Output Ready (OR) goes HIGH, indicating the presence of valid data. When the OR is HIGH, data may be shifted out by bringing the Shift Out (SO) HIGH. A HIGH signal at SO causes the OR to go LOW. Valid data is maintained while the SO is HIGH. When SO is brought LOW the upstream data, provided that stage has valid data, is shifted to the output stage. When new valid data is shifted to the output stage. OR goes HIGH. If the FIFO is emptied, OR stays LOW, and O<sub>X</sub> remains as before, (i.e. data does not change if FIFO is empty). Input Ready and Output Ready may also be used as status signals indicating that the FIFO is completely full (Input Ready stays LOW for at least tpT).

#### AC TEST AND HIGH-SPEED APP. NOTES

Since the FIFO is a very-high-speed device, care must be exercised in the design of the hardware and the timing utilized within the design. The internal shift rate of the FIFO typically exceeds 20 MHz in operation. Device grounding and decoupling is crucial to correct operation as the FIFO will respond to very small glitches due to long reflective lines, high capacitance and/or poor supply decoupling and grounding. We recommend a monolithic ceramic capacitor of 0.1  $\mu$ F directly between V<sub>CC</sub> and GND with very short lead length. In addition, care must be exercised in how the timing is set up and how the parameters are measured. For example, since an AND gate function is associated with both the Shift

In-Input Ready combination, as well as the Shift Out-Output Ready combination, timing measurements may be misleading, i.e. rising edge of the Shift-In pulse is not recognized until Input-Ready is High. If Input-Ready is not high due to too high a frequency or FIFO being full or affected by Master Reset, the Shift-In activity will be ignored. This will affect the device from a functional standpoint, and will also cause the "effective" timing of Input Data Time (t<sub>IDH</sub>) and the next activity of Input Ready (t<sub>IRL</sub>) to be extended relative to Shift-In going High. This same type of problem is also related to t<sub>IRH</sub>, t<sub>ORL</sub> and t<sub>ORH</sub> as related to Shift-Out.



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3 Shift In is held HIGH.

As soon as Input Ready becomes HIGH the Input Data is loaded into the first word.

5 The Data from the first word is released for "fall through" to second word.



(1) The diagram assumes, that at this time, words 63, 62, 61 are loaded with A, B, C Data, respectively.

(2) Data is shifted out when Shift Out makes a HIGH to LOW transition.

Figure 5. Output Timing





(1) The diagram assumes, that at this time, words 63, 62, 61 are loaded with A, B, C Data, respectively.

2 Data in the crosshatched region may be A or B Data.





Output Ready HIGH indicates that data is available and a Shift Out pulse may be applied.
Shift Out goes HIGH causing the next step.
Output Ready goes LOW.
Contents of word 62 (B-DATA) is released for "fail through" to word 63.
Output Ready goes HIGH indicating that new data (B) is now available at the FIFO outputs.
If the FIFO has only one word loaded (A-DATA) then Output Ready stays LOW and the A-DATA remains unchanged at the outputs.
NOTE: Shift Out pulses applied when Output Ready is LOW will be ignored.





Figure 11. Cascading FIFOs to Form 128x4 FIFO with C5/C67401A/1

FIFOs can be easily cascaded to any desired depth. The handshaking and associated timing between the FIFOs are handled by the FIFOs themselves.



Figure 12. 192x12 FIFO with C5/C67401/1A

FIFOs are expandable in depth and width. However, in forming wider words two external gates are required to generate composite Input and Output Ready flags. This need is due to the different fall-through times of the FIFOs.

## **APPLICATIONS**



NOTE: The output of monostable holds off the "Buffer full" interrupt for 100ns. If 100ns after shift in, there has not been an input Ready to reset the "D Filp-flop" an interrupt is issued, as the FIFO is full. The CPU then empties the FIFO before the next character is output from the tape drive.







Figure 14. Bidirectional FIFO Application